

Electronic supplementary information (ESI)

Topological Insulator Bi_2Se_3 Nanowire/Si Heterostructure Photodetector with Ultrahigh Responsivity and Broadband Response

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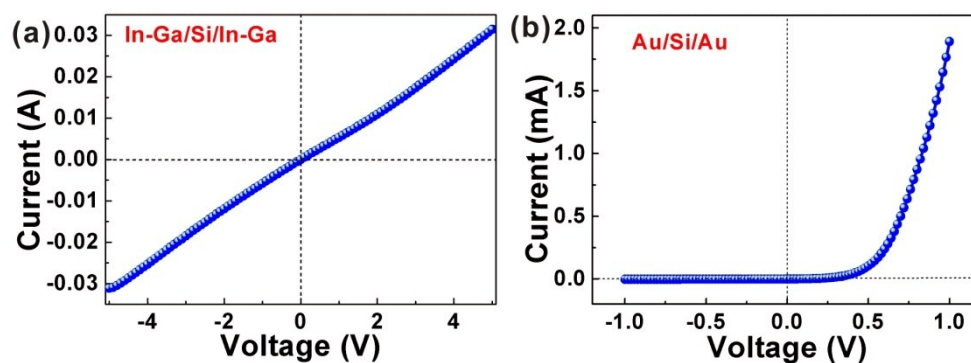


Fig. S1 I-V curves of the In-Ga/Si/In-Ga and Au/Si/Au devices.

Table. S1 Components of an individual Bi_2Se_3 NW

Element	Weight %	Atomic %
Se	28.86	51.77
Bi	71.13	48.22

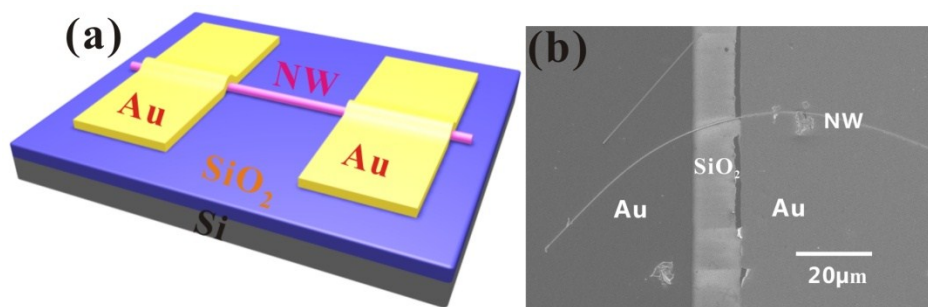


Fig. S2 (a) Schematic illustration of the Bi_2Se_3 NW based device with Au Ohmic contacts. (b) Typical SEM image of the Ohmic contact device.

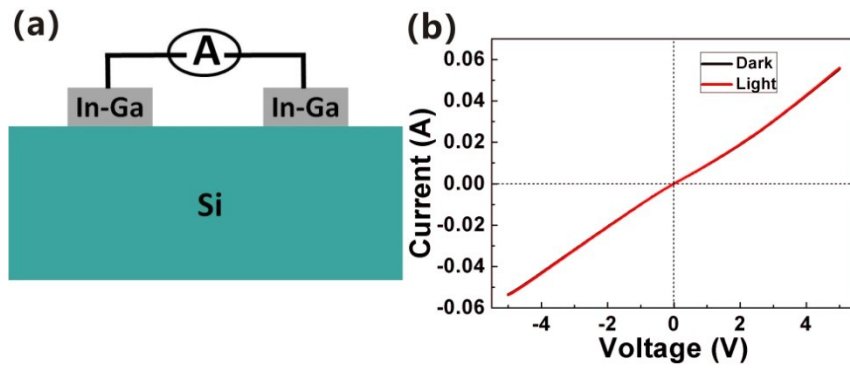


Fig. S3 (a), (b) were the schematic illustration and photoresponse of the In-Ga/Si/In-Ga device.

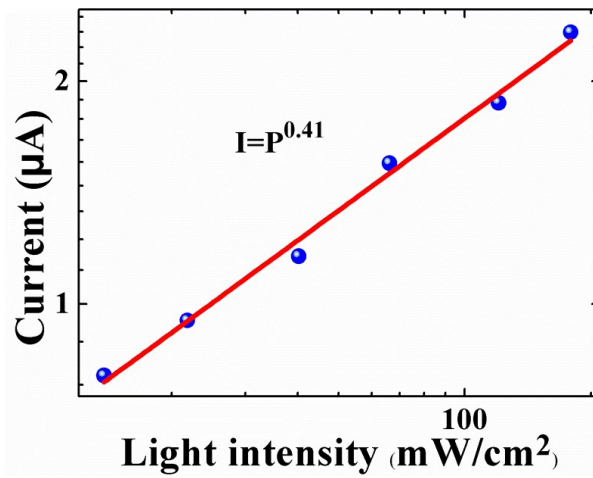


Fig. S4 Photocurrent of the Bi_2Se_3 NW/Si heterostructure as a function of light intensity. The curve can be fitted according to power law.

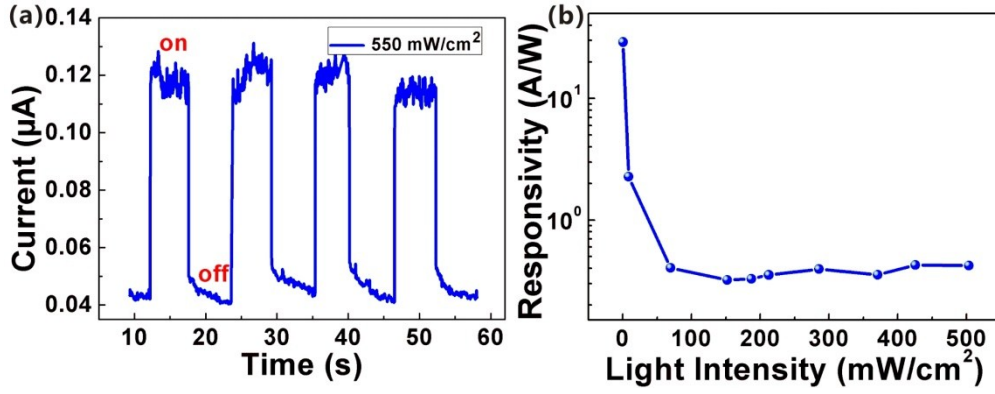


Fig. S5 (a) Photoresponse of the device measured at bias voltage of -5 V under the illumination of 1064 nm light. (b) Responsivity of the device as a function of light intensity under 1064 nm light illumination.

Table. S2 Statistics of responsivities of six devices (with number from 1-6)

Devices	1	2	3	4	5	6
R ($A W^{-1}$)	924.2	312.5	437.5	143.75	490.63	343.7

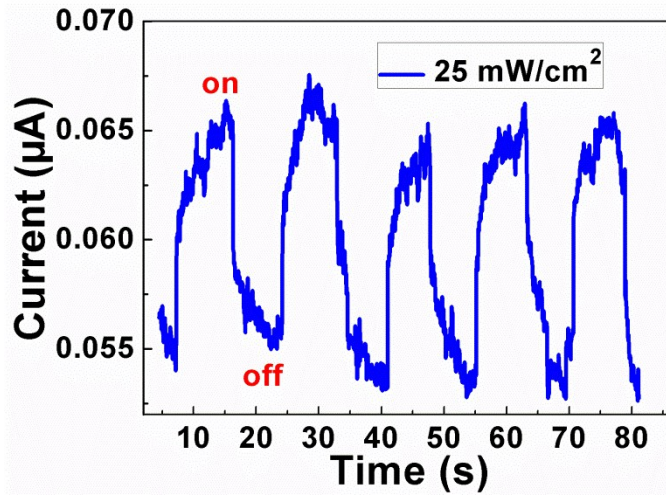


Fig. S6 Photoresponse of the devices measured under the illumination of 1310 nm light (25 mW cm^{-2}). The bias voltage was fixed at -5 V.

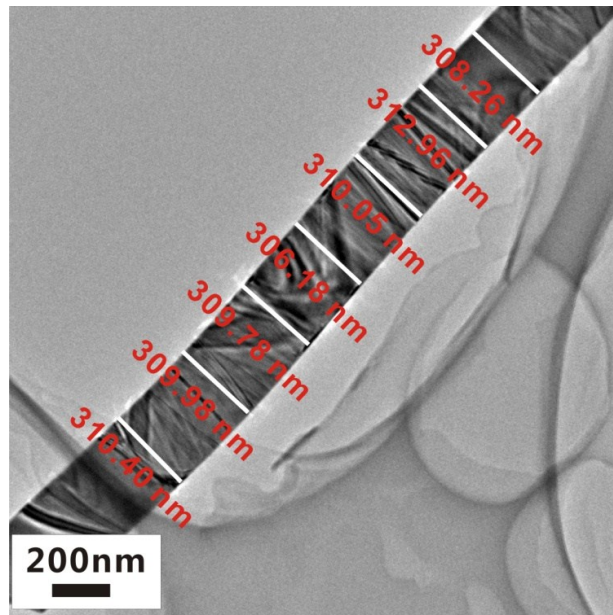


Fig. S7 Low-resolution TEM image of a single Bi₂Se₃ NW. The diameter of the NW can be deduced to be 309.66 ± 3.48 nm by measuring different positions in a single NW, and the mean error was less than 1.13%.

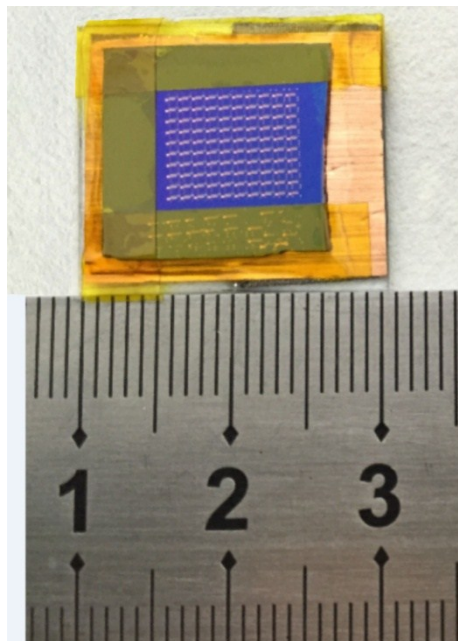


Fig. S8 Photograph of the Bi₂Se₃ NWs/Si heterostructure photodetectors, consisting of 10×10 devices in the same substrate.

Formulae's used in the study:

Work function	$\Phi_s = h\nu - E_{\max}$
Photocurrent	$I_{\text{ph}} = I_{\text{light}} - I_{\text{dark}}$
On/off ratio	On/off ratio = $I_{\text{light}}/I_{\text{dark}}$
Responsivity	$R \text{ (A W}^{-1}\text{)} = I_{\text{ph}}/P_{\text{in}}$
Detectivity	$D^* = (AB)^{1/2}/NEP \approx A^{1/2}R/(2qI_d)^{1/2}$
Gain	$G = R hc/(q\lambda)$

Where Φ_s = Work function (eV)

$h\nu$ = the energy of the He I radiation source (eV)

E_{\max} = maximum binding energy (eV)

I_{ph} = photocurrent (μA)

I_d = the dark current (μA)

R = Responsivity (A W^{-1})

P_{in} = the incident light power on the active area of the photodetector (mW cm^{-2})

D^* = Detectivity (Jones)

A = the active area of the photodetector (cm^2)

B = the bandgap (eV)

NEP = the noise equivalent power (W)

q = the unit charge (C)

h = the Planck's constant (J s)

c = the velocity of light (m s^{-1})

λ = the wavelength of illuminated light (nm)